STANDARD

4288

Second edition
1996-08-01

Geometrical Product Specifications (GPS) — Surface texture: Profile method — Rules and procedures for the assessment of surface texture

Spécification géométrique des produits (GPS) — État de surface: Méthode du profil — Règles et procédures pour l'évaluation de l'état de surface

Reference Number
ISO 4288:1996(E)

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

International Standard ISO 4288 was prepared jointly by Technical Committees ISO/TC 57, *Metrology and properties of surfaces*, Subcommittee SC 1, *Geometrical parameters — Instruments and procedures for measurement of surface roughness and waviness*, ISO/TC 3, *Limits and fits* and ISO/TC 10, *Technical drawings, product definition and related documentation*, Subcommittee SC 5, *Dimensioning and tolerancing*.

This second edition cancels and replaces the first edition (ISO 4288:1985) which has been technically revised.

It differs from the previous edition in that filter cut-off values are chosen based on the workpiece texture rather than the drawing indication. Furthermore, this International Standard includes rules for the determination of parameters other than Ra and Rz. This second edition covers roughness profile parameters, primary profile parameters and comparison of measured motif parameter values with given specification.

It is envisaged that an amendment will be prepared covering M-system waviness profile parameters, for which there are currently no standardized rules.

Annexes A, B and C of this International Standard are for information only.